

ESD TEST REPORT

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| Field-Induced Charged-Device Model |
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| JS-002-2014 |
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ANSI/ESDA/JEDEC Standard, Method JS-002-2014 is an ESD test using Field-Induced Charged-Device Model, three positive and three negative pulses applied to the devices per customer's specification with 0.5 second cool down between pulses.

Customer : **Chongqing Alpha and Omega Semiconductor Limited**

Address: No. 288 Yuefu Road, Beibei District, Chongqing, P.R. China

Device Information

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|----------------|-------------|---------------|-------|
| Part No. : | AOCA24106C | Sample Size : | 3pcs |
| Package Type : | MCSP1.9X1.6 | Pin Count : | 6 |
| Lot No. : | 9C01 | Date Code : | - |
| VDD Domains : | S2 S1 | VSS Domains : | S1 S2 |

Test Equipment

| | | | |
|--------------------|-------------------------------|-------------------|---------------------------|
| Tester1 : | ZAPMASTER MK.2 SE | Serial No. : | 0508317 |
| Calibration Date : | Jun 20 th 2019 | Expiration Date : | Jun 19 th 2020 |
| Tester2 : | Orion Robotic CDM Test System | Serial No. : | 0806294 |
| Calibration Date : | Oct 11 th 2019 | Expiration Date : | Oct 10 th 2020 |

Environmental Condition

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|---------------|---------------------------|-----------------|---------------------------|
| Temperature : | 23°C | Humidity : | 30% RH |
| Submit date : | Dec 27 th 2019 | Complete date : | Dec 27 th 2019 |

Stress Summary

| CDM | | | |
|------------|---------------|---------------|--|
| Sample No. | Voltage Level | Process | Spot Test Results* (Within 10µA @ 8V between G and S2/S1) |
| 9# | ±2kV | All Pins Done | PASS |
| 10# | | All Pins Done | PASS |
| 11# | | All Pins Done | PASS |

Test Result*

| Model | Pin Combinations | ESD Sensitivity Pass*: 2kV | V Class: C3 |
|-------|------------------|-----------------------------------|---|
| CDM | ALL PINS DONE | ±2kV | JS-002-2014 Class C0a: <125V Class C0b: 125V to <250V Class C1: 250 to <500 V Class C2a: 500 to <750 V Class C2b: 750 to <1000 V Class C3: ≥1000V |

*Note: Results will be updated based on customer final electrical test results.

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| Test Engineer: Wenping Yan | Date: Dec 27 th 2019 |  |
| Approved by Technical Director:  | Date: Dec 27 th 2019 | |

Recommendations

EAG Shanghai certifies that above tests have been performed in accordance to the requirements stated above and per the customer purchase order and applicable documents.

EAG Shanghai recommends electrical testing as a validation of reported results. Curve Trace criteria was utilized to specify a pass or fail. Industry standards require the device to be tested functionally at post stress and should continue to meet all electrical parameters as per the data sheet.

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